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The application domain of the published articles is electronic circuits and systems used for computing and communications. Broadly, the topics include hardware testing, verification, design for testability, reliability and security.

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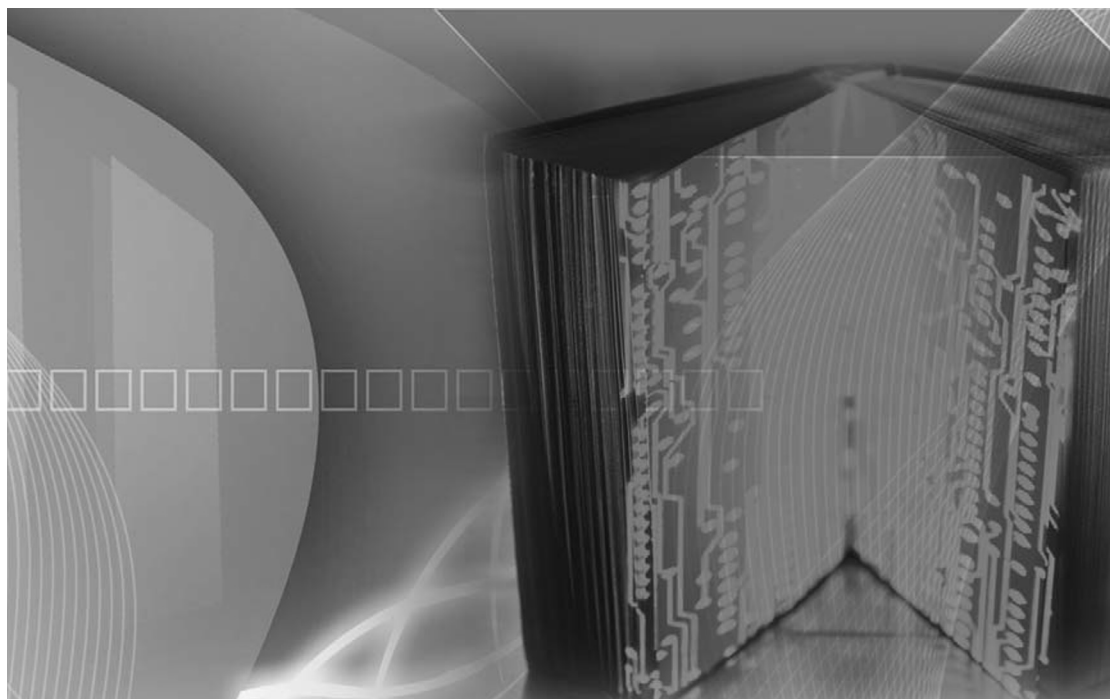
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